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## CLAIMS

- 1. An apparatus coupled to a low speed tester and a device, wherein said apparatus is configured to allow said low speed tester to perform high speed tests of said device.
- 2. The apparatus according to claim 1, wherein said low speed tester is further configured to control high-speed transmit, reception and verification of said device.
- 3. The apparatus according to claim 1, wherein said device comprises a Universal Serial Bus (USB) device.
- 4. The apparatus according to claim 1, further comprising:
  - a host emulator configured to interface said device; and a test vector generator.
- 5. The apparatus according to claim 4, wherein said low speed/tester is configured to control said host emulator.

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- 6. The apparatus according to claim 4, wherein said low speed tester is configured in response to one or more test vectors.
- 7. The apparatus according to claim 6, wherein said test vector generator is configured to generate said one or more test vectors.
- 8. The apparatus according to claim 1, wherein said apparatus is further configured to test a reception and transmission operation of said device.
- 9. The apparatus according to claim 1, wherein said apparatus is further configured to initiate one or more test packets.
- 10. The apparatus according to claim 9, wherein said device is further configured to receive and verify said one or more test packets.

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- 11. The apparatus according to claim 10, wherein said device is further configured to transmit said one or more test packets.
- 12. The apparatus according to claim 4, wherein said apparatus is further configured to receive and verify said one or more transmitted test packets.
- 13. The apparatus according to claim 1, wherein said low speed tester is further configured to generate a pass/fail signal.
- 14. The apparatus according to claim 1, wherein said apparatus is configured to perform at least one test of a plurality of test modes wherein said plurality of test modes comprise USB 2.0 defined test modes for use in a production test environment.
  - 15. An apparatus comprising:

means for testing a device; and

means for configuring a low speed tester to perform high speed tests of said device.

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- 16. A method for testing a device comprising the steps of:
  - (A) testing a device; and
- (B) configuring a low speed tester to perform high speed tests of said device.
- 17. The method according to claim 16, wherein said device under test comprises an USB device.
- 18. The method according to claim 15, wherein step (B) further comprises:

configuring said low speed tester to control a host emulation.

19. The method according to claim 18, wherein step (B) further comprises:

allowing said host emulator to interface with said device under test.

20. The method according to claim 16, further comprising performing at least one of a plurality of test modes wherein the

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plurality of test modes comprise USB 2.0 defined test modes for use in a production test environment